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SERIAL NUMBER 10/796,672	FILING OR 371(c) DATE 03/09/2004 RULE	CLASS 257	GROUP ART UNIT 2815	ATTORNEY DOCKET NO. 5649-1276	
APPLICANTS Young-pil Kim, Gyeonggi-do, KOREA, REPUBLIC OF; Beom-jun Jin, Seoul, KOREA, REPUBLIC OF; ** CONTINUING DATA ***** None MCL ** FOREIGN APPLICATIONS ***** Yes MCL REPUBLIC OF KOREA 2003-18588 03/25/2003 IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 05/25/2004					
Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 (a-d) conditions <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after met Verified and Acknowledged <u>Matthew P. [Signature]</u> Examiner's Signature Initials		STATE OR COUNTRY KOREA, REPUBLIC OF	SHEETS DRAWING 21	TOTAL CLAIMS 42	INDEPENDENT CLAIMS 4
ADDRESS D. Randal Ayers Myers Bigel Sibley & Sajovec Post Office Box 37428 Raleigh, NC27627					
TITLE Semiconductor device test patterns and related methods for precisely measuring leakage currents in semiconductor cell transistors					
FILING FEE RECEIVED 1252	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit		